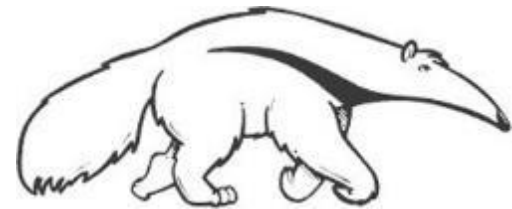


Machine Learning and Data Mining

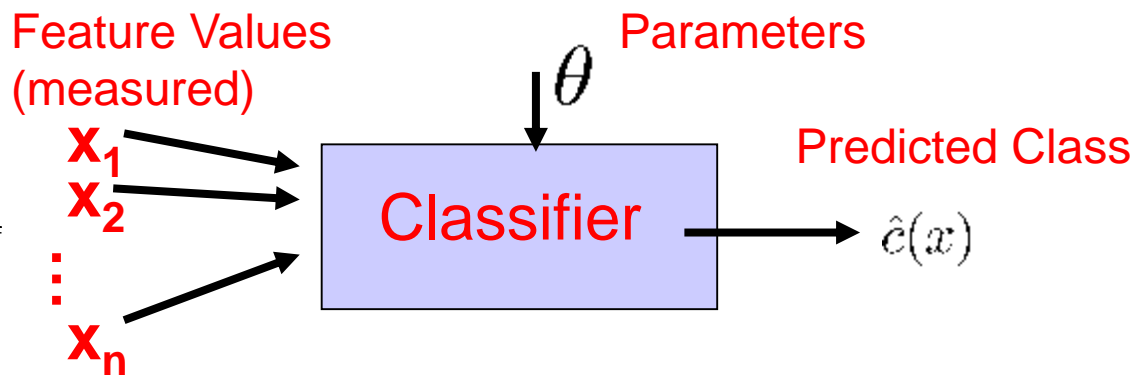
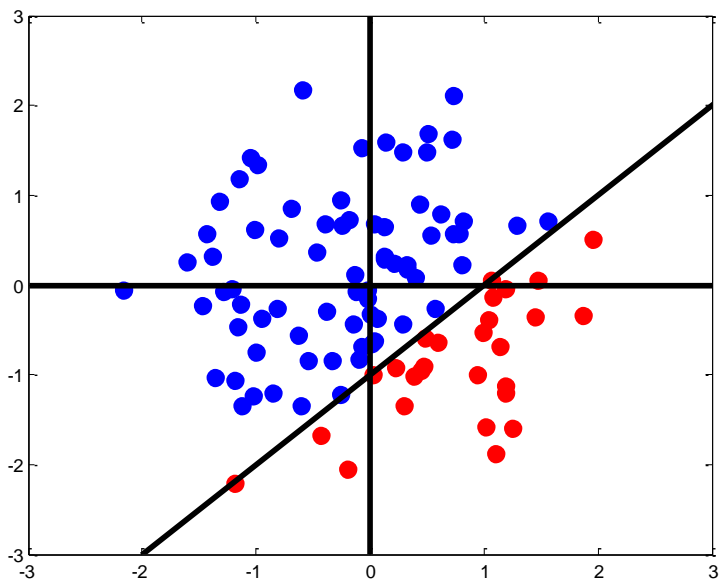
VC Dimension

Kalev Kask



Learners and Complexity

- We've seen many versions of underfit/overfit trade-off
 - Complexity of the learner
 - “Representational Power”
- Different learners have different power

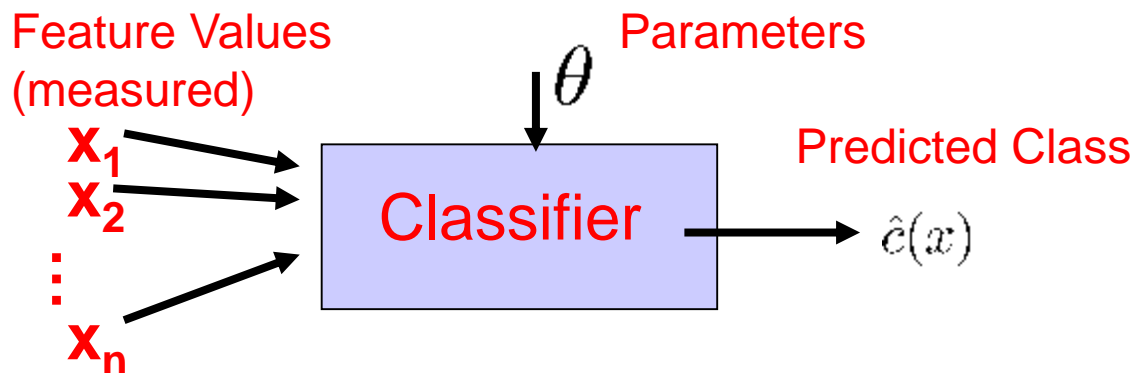
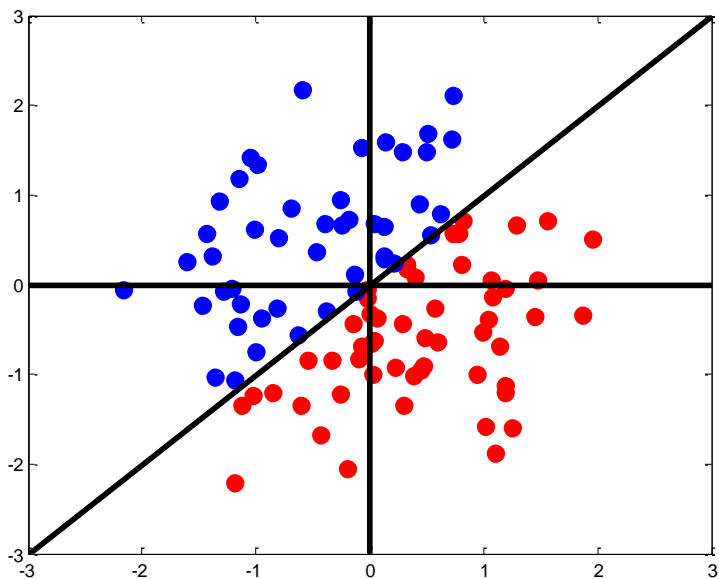


Example:

$$\hat{c}(x) = \text{sign}(\theta_1 x_1 + \theta_2 x_2 + \theta_0)$$

Learners and Complexity

- We've seen many versions of underfit/overfit trade-off
 - Complexity of the learner
 - “Representational Power”
- Different learners have different power

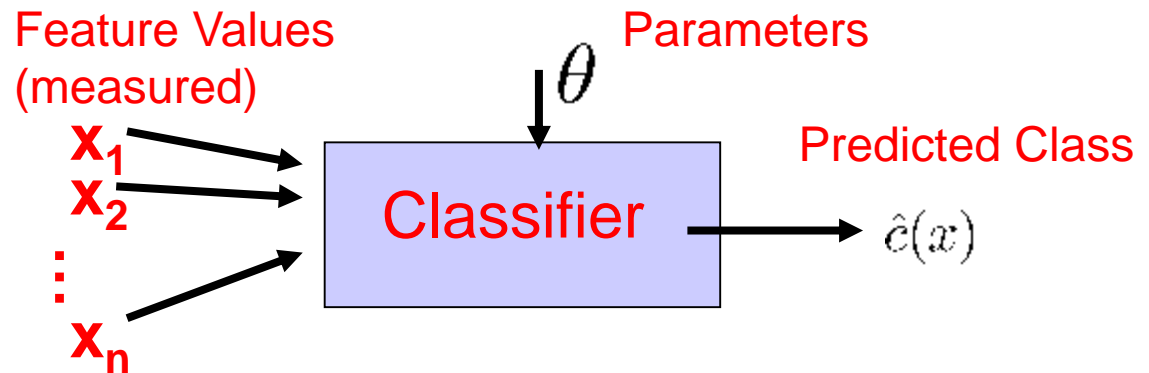
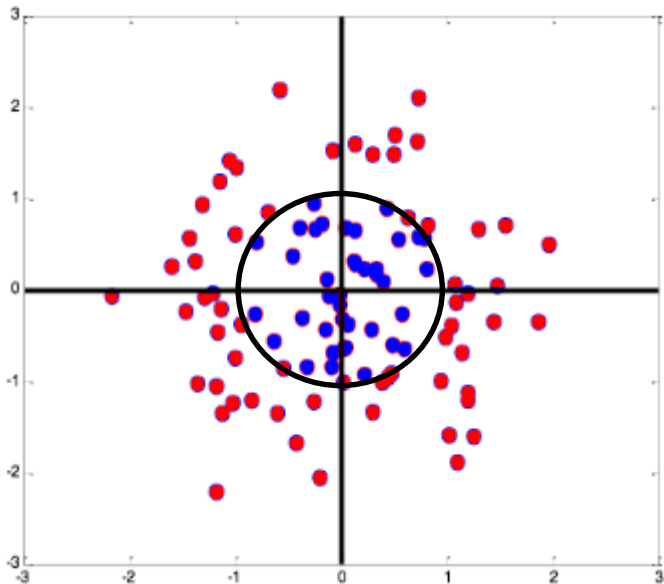


Example:

$$\hat{c}(x) = \text{sign}(\theta_1 x_1 + \theta_2 x_2)$$

Learners and Complexity

- We've seen many versions of underfit/overfit trade-off
 - Complexity of the learner
 - “Representational Power”
- Different learners have different power



Example:

$$\hat{c}(x) = \text{sign}((x_1^2 + x_2^2) - \theta_0)$$

Learners and Complexity

- We've seen many versions of underfit/overfit trade-off
 - Complexity of the learner
 - “Representational Power”
- Different learners have different power
- Usual trade-off:
 - More power = represent more complex systems, might overfit
 - Less power = won't overfit, but may not find “best” learner
- How can we quantify representational power?
 - Not easily...
 - One solution is VC (Vapnik-Chervonenkis) dimension

Some notation

- Assume training data are iid from some distribution $p(x,y)$
- Define “risk” and “empirical risk”
 - These are just “long term” test and observed training error

$$R(\theta) = \text{TestError} = \mathbb{E}[\mathbb{1}[c \neq \hat{c}(x; \theta)]]$$

$$R^{\text{emp}}(\theta) = \text{TrainError} = \frac{1}{m} \sum_i \mathbb{1}[c^{(i)} \neq \hat{c}(x^{(i)}; \theta)]$$

- How are these related? Depends on overfitting...
 - Underfitting domain: pretty similar...
 - Overfitting domain: test error might be lots worse!

VC Dimension and Risk

- Given some classifier, let H be its VC dimension
 - Represents “representational power” of classifier

$$R(\theta) = \text{TestError} = \mathbb{E}[\mathbb{1}[c \neq \hat{c}(x; \theta)]]$$

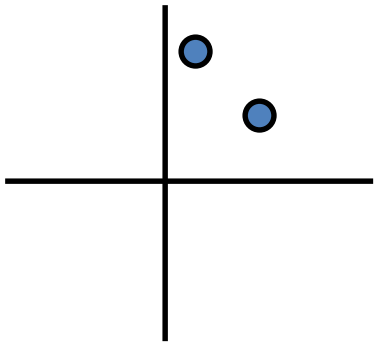
$$R^{\text{emp}}(\theta) = \text{TrainError} = \frac{1}{m} \sum_i \mathbb{1}[c^{(i)} \neq \hat{c}(x^{(i)}; \theta)]$$

- With “high probability” $(1 - \eta)$, Vapnik showed

$$\text{TestError} \leq \text{TrainError} + \sqrt{\frac{H \log(2m/H) + H - \log(\eta/4)}{m}}$$

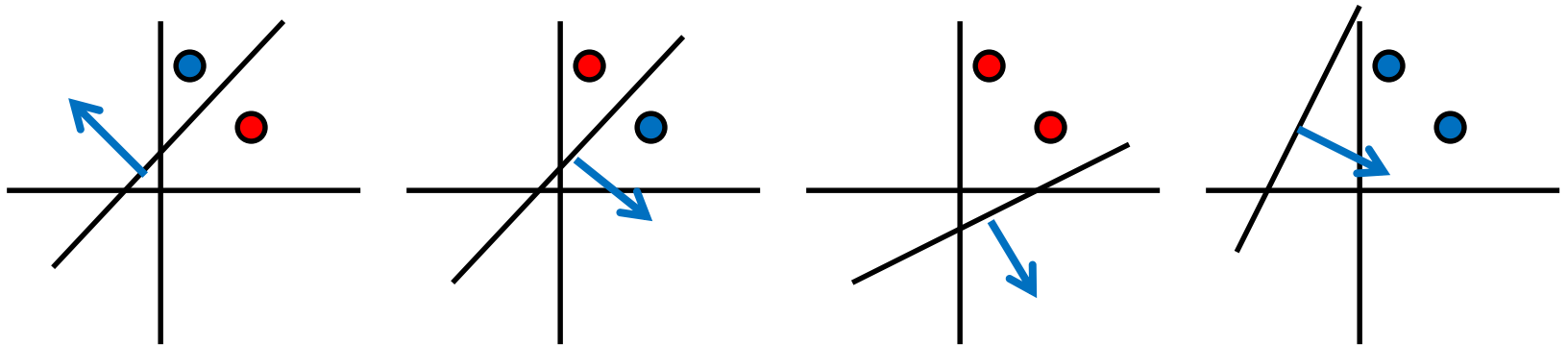
Shattering

- We say a classifier $f(x)$ can shatter points $x^{(1)} \dots x^{(h)}$ iff
For *all* $y^{(1)} \dots y^{(h)}$, $f(x)$ can achieve zero error on training data $(x^{(1)}, y^{(1)})$, $(x^{(2)}, y^{(2)})$, ... $(x^{(h)}, y^{(h)})$
(i.e., there exists some θ that gets zero error)
- Can $f(x; \theta) = \text{sign}(\theta_0 + \theta_1 x_1 + \theta_2 x_2)$ shatter these points?



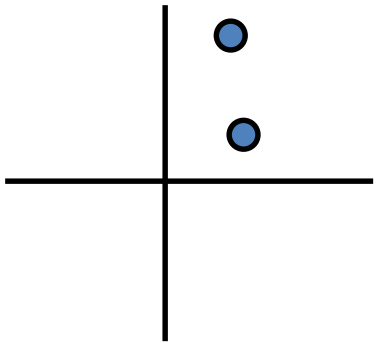
Shattering

- We say a classifier $f(x)$ can shatter points $x^{(1)} \dots x^{(h)}$ iff For *all* $y^{(1)} \dots y^{(h)}$, $f(x)$ can achieve zero error on training data $(x^{(1)}, y^{(1)})$, $(x^{(2)}, y^{(2)})$, ... $(x^{(h)}, y^{(h)})$ (i.e., there exists some θ that gets zero error)
- Can $f(x; \theta) = \text{sign}(\theta_0 + \theta_1 x_1 + \theta_2 x_2)$ shatter these points?
- Yes: there are 4 possible training sets...



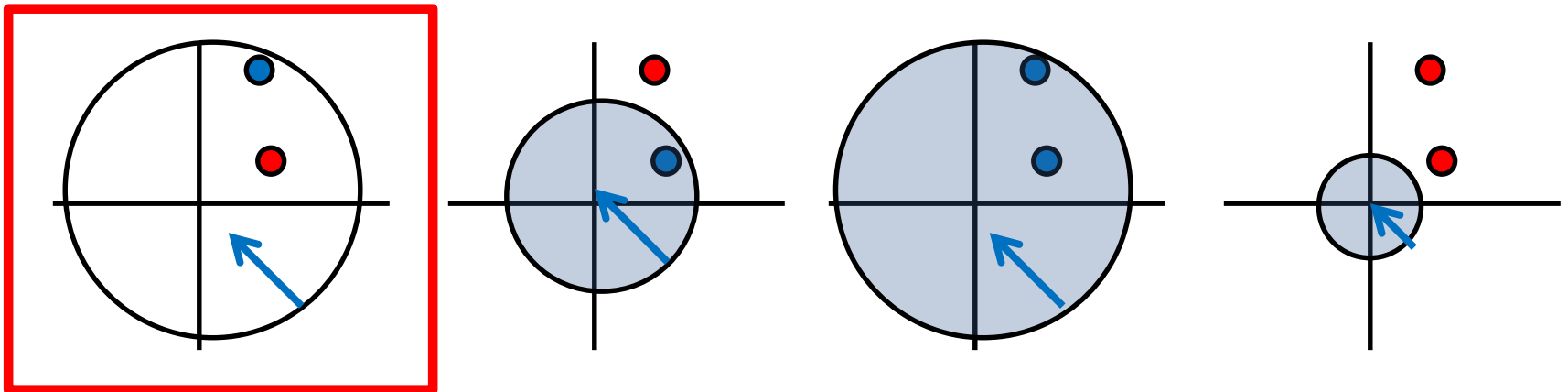
Shattering

- We say a classifier $f(x)$ can shatter points $x^{(1)} \dots x^{(h)}$ iff
For *all* $y^{(1)} \dots y^{(h)}$, $f(x)$ can achieve zero error on
training data $(x^{(1)}, y^{(1)})$, $(x^{(2)}, y^{(2)})$, ... $(x^{(h)}, y^{(h)})$
(i.e., there exists some θ that gets zero error)
- Can $f(x; \theta) = \text{sign}(x_1^2 + x_2^2 - \theta)$ shatter these points?



Shattering

- We say a classifier $f(x)$ can shatter points $x^{(1)} \dots x^{(h)}$ iff For *all* $y^{(1)} \dots y^{(h)}$, $f(x)$ can achieve zero error on training data $(x^{(1)}, y^{(1)})$, $(x^{(2)}, y^{(2)})$, ... $(x^{(h)}, y^{(h)})$ (i.e., there exists some θ that gets zero error)
- Can $f(x; \theta) = \text{sign}(x_1^2 + x_2^2 - \theta)$ shatter these points?
- Nope!



VC Dimension

- The VC dimension H is defined as

The maximum number of points h that *can be arranged* so that $f(x)$ can shatter them

- A game:

- Fix the definition of $f(x; \theta)$
- Player 1: choose locations $x^{(1)} \dots x^{(h)}$
- Player 2: choose target labels $y^{(1)} \dots y^{(h)}$
- Player 1: choose value of θ
- If $f(x; \theta)$ can reproduce the target labels, P1 wins

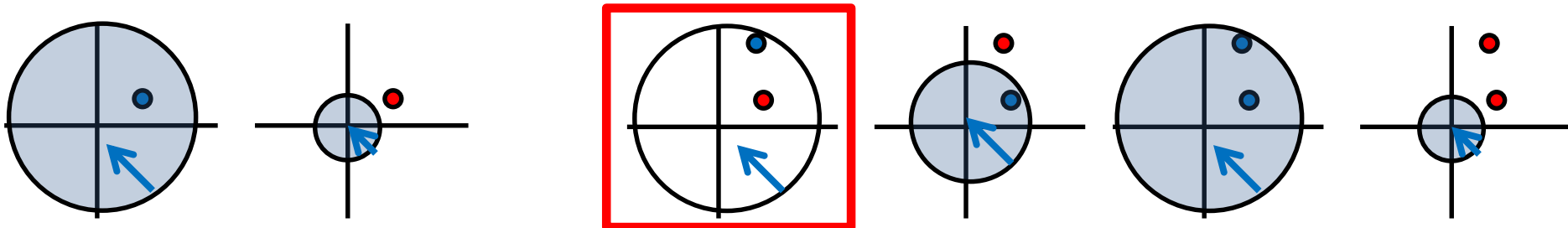
$$\exists \{x^{(1)} \dots x^{(h)}\} \text{ s.t. } \forall \{y^{(1)} \dots y^{(h)}\} \exists \theta \text{ s.t. } \forall i \ f(x^{(i)}; \theta) = y^{(i)}$$

VC Dimension

- The VC dimension H is defined as
The maximum number of points h that *can be arranged* so that $f(x)$ can shatter them
- Example: what's the VC dimension of the (zero-centered) circle, $f(x; \theta) = \text{sign}(x_1^2 + x_2^2 - \theta)$?

VC Dimension

- The VC dimension H is defined as
The maximum number of points h that *can be arranged* so that $f(x)$ can shatter them
- Example: what's the VC dimension of the (zero-centered) circle, $f(x; \theta) = \text{sign}(x_1^2 + x_2^2 - \theta)$?
- VCdim = 1 : can arrange one point, cannot arrange two (previous example was general)

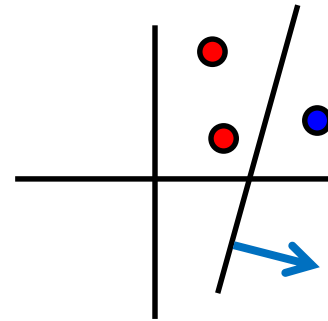


VC Dimension

- Example: what's the VC dimension of the two-dimensional line, $f(x;\theta) = \text{sign}(\theta_1 x_1 + \theta_2 x_2 + \theta_0)$?

VC Dimension

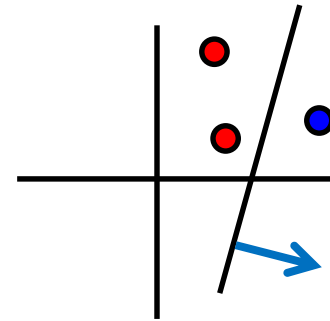
- Example: what's the VC dimension of the two-dimensional line, $f(x;\theta) = \text{sign}(\theta_1 x_1 + \theta_2 x_2 + \theta_0)$?
- VC dim ≥ 3 ? Yes



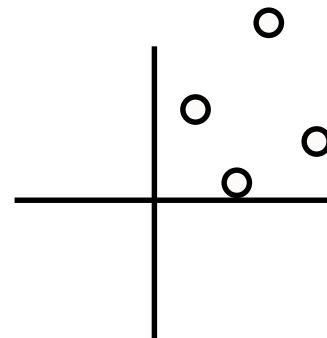
VC Dimension

- Example: what's the VC dimension of the two-dimensional line, $f(x;\theta) = \text{sign}(\theta_1 x_1 + \theta_2 x_2 + \theta_0)$?

- VC dim ≥ 3 ? Yes



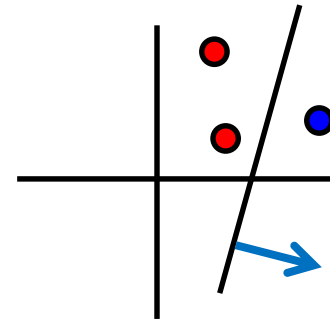
- VC dim ≥ 4 ?



VC Dimension

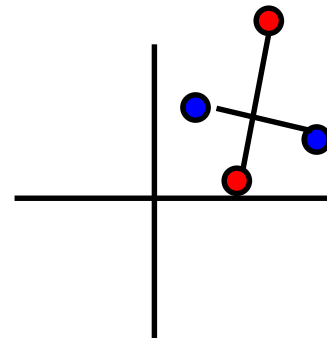
- Example: what's the VC dimension of the two-dimensional line, $f(x;\theta) = \text{sign}(\theta_1 x_1 + \theta_2 x_2 + \theta_0)$?

- VC dim ≥ 3 ? Yes



- VC dim ≥ 4 ? No...

Any line through these points must split one pair (by crossing one of the lines)



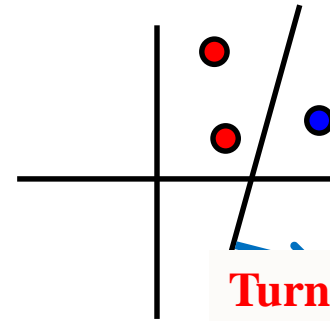
VC Dimension

- Example: what's the VC dimension of the two-dimensional line, $f(x;\theta) = \text{sign}(\theta_1 x_1 + \theta_2 x_2 + \theta_0)$?

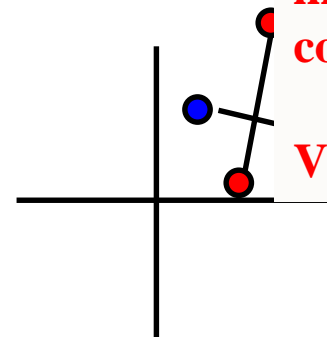
- VC dim ≥ 3 ? Yes

- VC dim ≥ 4 ? No...

Any line through these points must split one pair (by crossing one of the lines)



Turns out:
For a general, linear classifier (perceptron) in d dimensions with a constant term:



VC dim = $d+1$

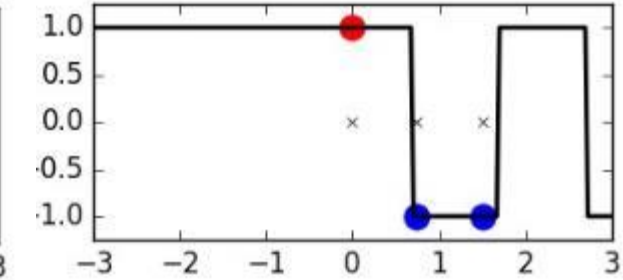
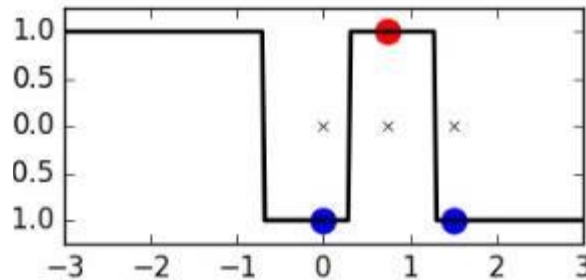
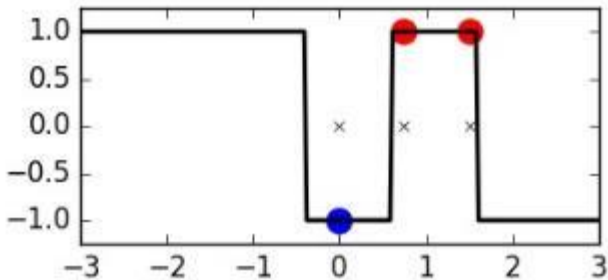
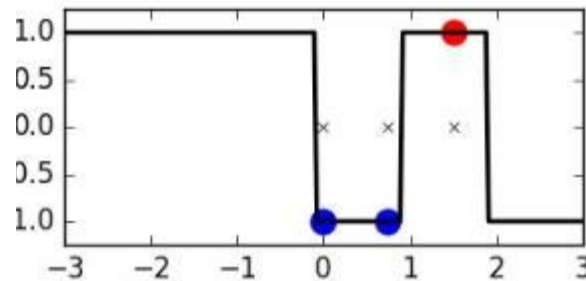
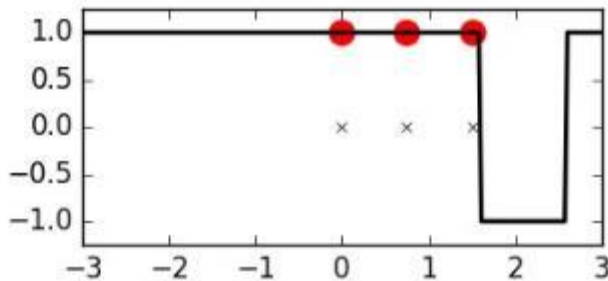
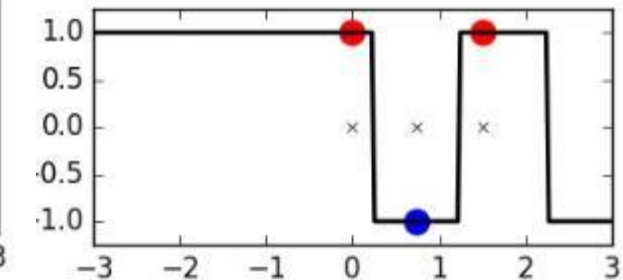
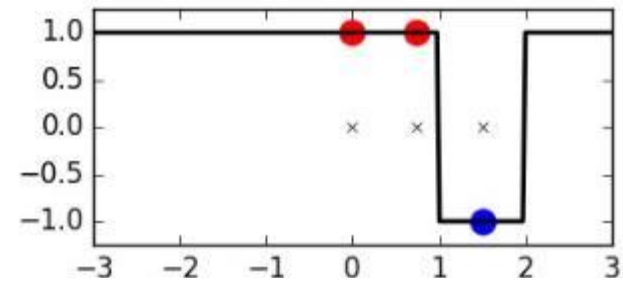
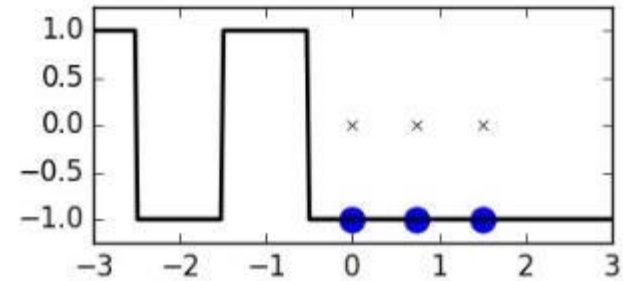
VC Dimension

- VC dimension measures the “power” of the learner
- Does *not* necessarily equal the # of parameters!
- Number of parameters does not necessarily equal complexity
 - Can define a classifier with a lot of parameters but not much power (how?)
 - Can define a classifier with one parameter but lots of power (how?)
- Lots of work to determine what the VC dimension of various learners is...

Example

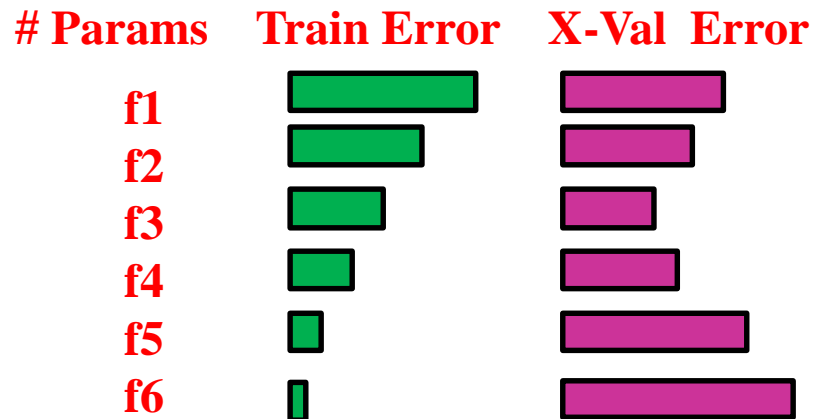
$$f(x; t) = \begin{cases} +1 & x \in [-\inf, t] \cup [t + 1, t + 2] \\ -1 & \text{otherwise} \end{cases}$$

- VC Dim ≥ 3 ?
- VC Dim ≥ 4 ?



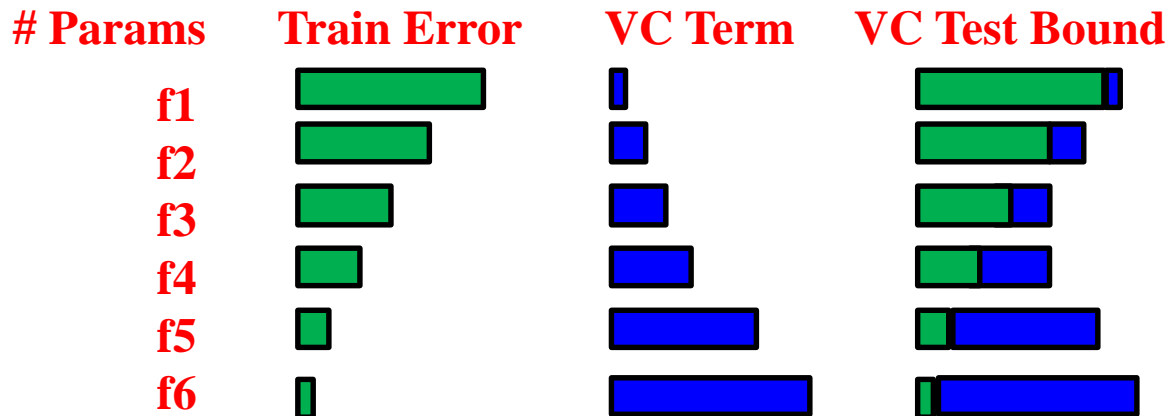
Using VC dimension

- Used validation / cross-validation to select complexity



Using VC dimension

- Used validation / cross-validation to select complexity
- Use VC dimension based bound on test error similarly
- “Structural Risk Minimization” (SRM)



Using VC dimension

- Used validation / cross-validation to select complexity
- Use VC dimension based bound on test error similarly
- Other Alternatives
 - Probabilistic models: likelihood under model (rather than classification error)
 - AIC (Aikike Information Criterion)
 - Log-likelihood of training data - # of parameters
 - BIC (Bayesian Information Criterion)
 - Log-likelihood of training data - (# of parameters)*log(m)
- Similar to VC dimension: performance + penalty
- BIC conservative; SRM very conservative
- Also, “true Bayesian” methods (take prob. learning...)